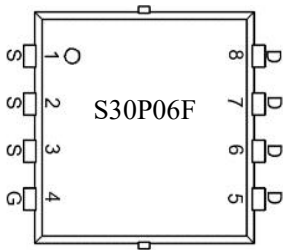
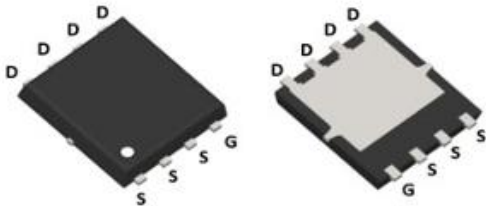
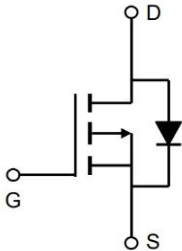


Features	Bvdss	Rdson	ID
	-60V	31mΩ	-30A
	Application		
➤ Split Gate Trench MOSFET technology ➤ Excellent package for heat dissipation ➤ High density cell design for low RDS(ON)	➤ Battery switching application ➤ Hard switched and high frequency circuits ➤ Power management		
RoHS			
Package			
			
Marking and pin assignment	PDFN5*6-8L top view		Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
30P06	S30P06F	PDFN5*6-8L	5000

Absolute Maximum Ratings ($T_J=25^{\circ}\text{C}$ unless otherwise specified)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	-60	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current, $V_{GS@-4.5V}^1$	$T_C=25^{\circ}\text{C}$	I_D	-30	A
	$T_C=100^{\circ}\text{C}$	I_D	-15	A
Pulsed Drain Current ²		I_{DM}	-120	A
Power Dissipation ³	$T_C = 25^{\circ}\text{C}$	P_D	89	W
Operating junction and storage temperature		T_J, T_{STG}	-55 ~ 150	$^{\circ}\text{C}$

Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-Case	$R_{\theta JC}$	1.4	$^{\circ}\text{C/W}$
Thermal resistance, junction – ambient	$R_{\theta JA}^*$	60	$^{\circ}\text{C/W}$



Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLS30P06F	PDFN5*6-8L	4	5,6,7,8	1,2,3	Tape Reel

Electrical Characteristics (T_j=25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-60	-	-	V
Gate-body Leakage current	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -60V, V _{GS} = 0V, T _J =25°C	-	-	1	μA
		V _{DS} = -60V, V _{GS} = 0V, T _J =55°C	-	-	5	
Gate-Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-1.3	-1.7	-2.3	V
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = -10V, I _D = -3A	-	31	38	mΩ
		V _{GS} = -4.5V, I _D = -2A	-	40	50	
Forward Transconductance	g _{fs}	V _{DS} = -5V, I _D = -3A	-	-	-	S
Input Capacitance	C _{ISS}	V _{DS} = -30V, V _{GS} = 0V, f = 1MHz	-	862	-	pF
Output Capacitance	C _{OSS}		-	163	-	
Reverse Transfer Capacitance	C _{RSS}		-	8	-	
Gate Resistance	R _g	V _{GS} =0V, V _{DS} =0V, f=1MHz	-	13	-	Ω
Total Gate Charge(-4.5V)	Q _g	V _{GS} = -10V, V _{DS} = -30V, I _D = -10A	-	13.4	-	nC
Gate-Source Charge	Q _{gs}		-	3.55	-	
Gate-Drain Charge	Q _{gd}		-	1.82	-	
Turn-On Delay Time	T _{d(on)}	V _{GS} = -10V, V _{DD} = -30V, RG = 5Ω, I _D = -10A	-	10	-	ns
Rise Time	T _R		-	6	-	
Turn-Off Delay Time	T _{d(off)}		-	23	-	
Fall Time	T _F		-	11	-	
Diode Forward Current ^{1,5}	I _S	V _G =V _D =0V, Force Current	-	-	-30	A
Diode Forward Voltage ²	V _{SD}	I _S =-1A, V _{GS} =0V, T _J =25°C	-	-	-1.2	V
Reverse Recovery time	T _{rr}	I _F =-10A, T _J =25°C dI/dt=100A/μs	-	18	-	ns
Reverse Recovery Charge	Q _{rr}		-	27	-	nC

Note :

1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%

3.The EAS data shows Max. rating . The test condition is V_{DD}=-30V, V_{GS}=-10V, L=1mH



4. The power dissipation is limited by 150°C junction temperature
5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

Typical Performance Characteristics

Fig1:Typ. output characteristics

$$I_D = f(V_{DS})$$

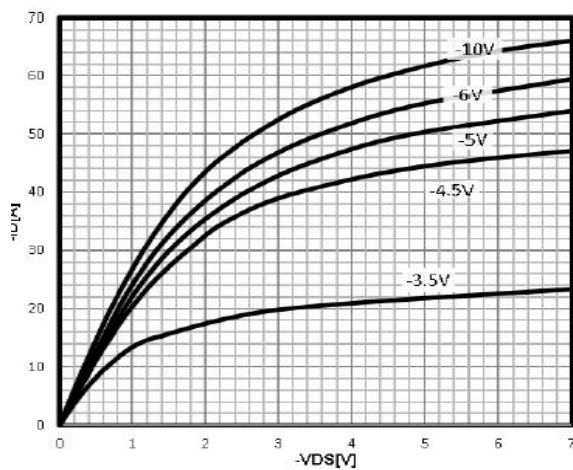


Fig2:Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D)$$

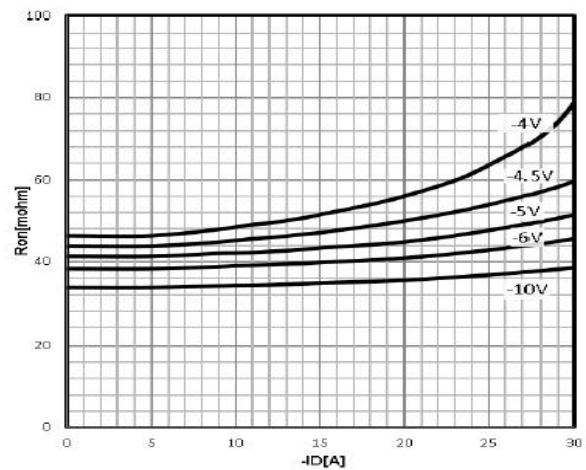


Fig3:Typ. transfer characteristics

$$-I_D = f(-V_{GS})$$

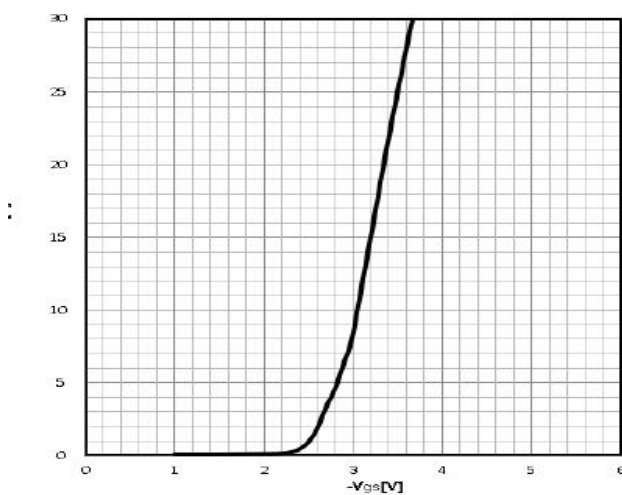


Fig4:Drain-source on-state resistance

$$R_{DS(on)} = f(T_J) |_{I_D = -20A; V_{GS} = -10V}$$

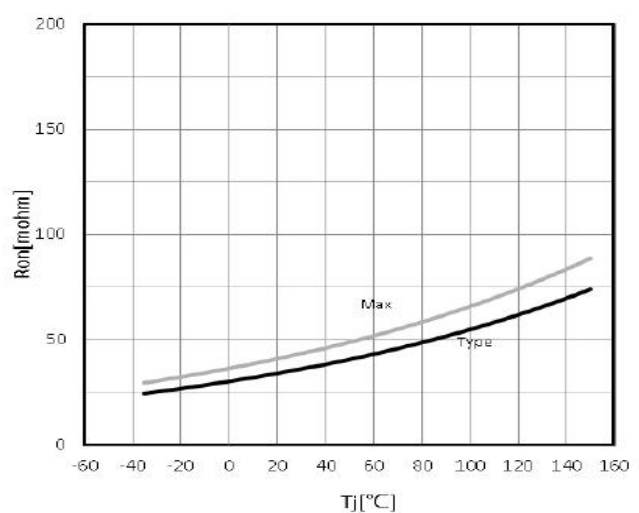


Fig5:Gate Threshold Voltage

$$-V_{TH}=f(T_j); I_D=-250\mu A$$

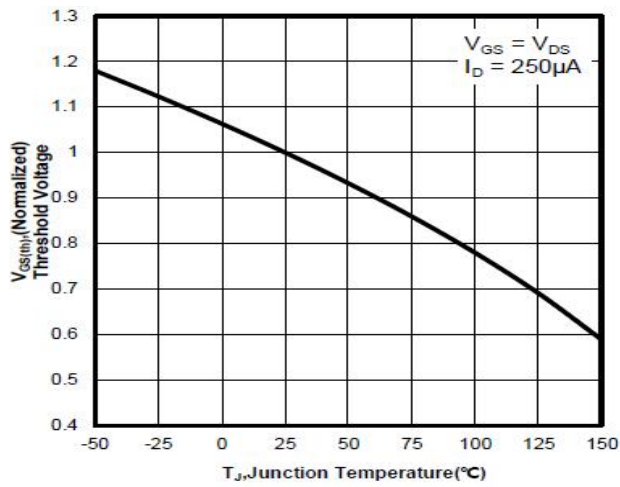


Fig6:Drain-source breakdown voltage

$$-V_{BR(DSS)}=f(T_j); I_D=-250\mu A$$

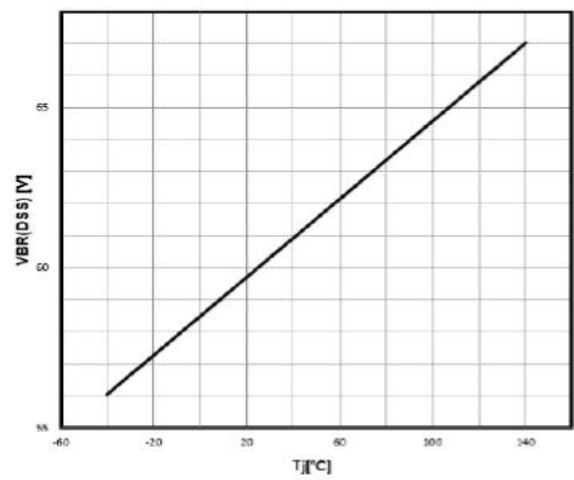


Fig7:Typ. gate charge

$$V_{GS}=f(Q_{gate}); I_D=-20A$$

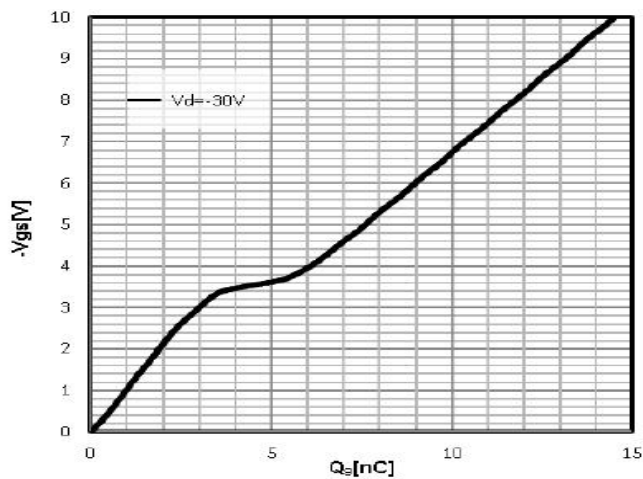


Fig8:Typ. Capacitances

$$C=f(-V_{DS}); V_{GS}=0V; f=1MHz$$

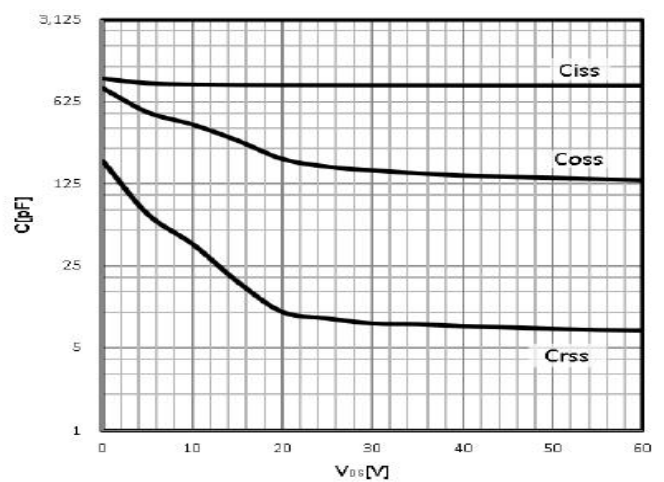


Fig9:Power Dissipation

$$P_{tot}=f(T_c)$$

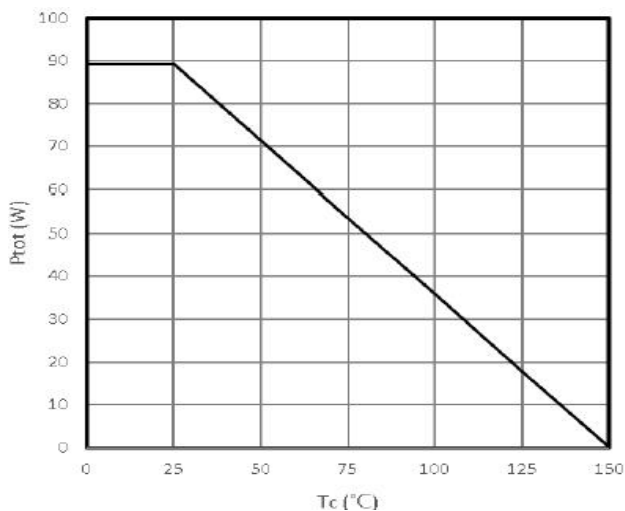


Fig10:Maximum Drain Current

$$-I_D=f(T_c)$$

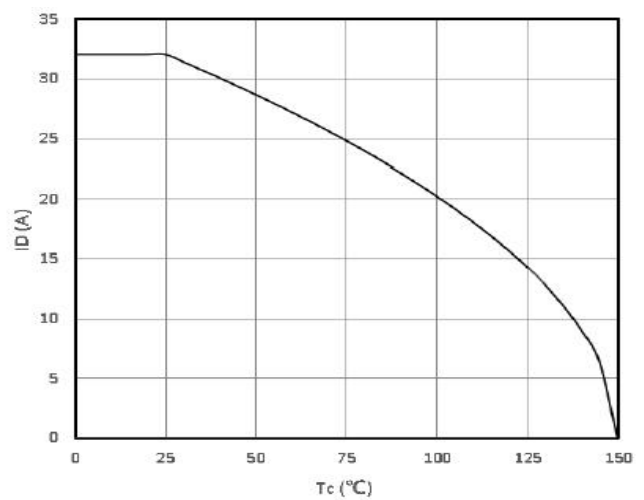


Fig11:Safe operating area

$$-I_D = f(-V_{DS})$$

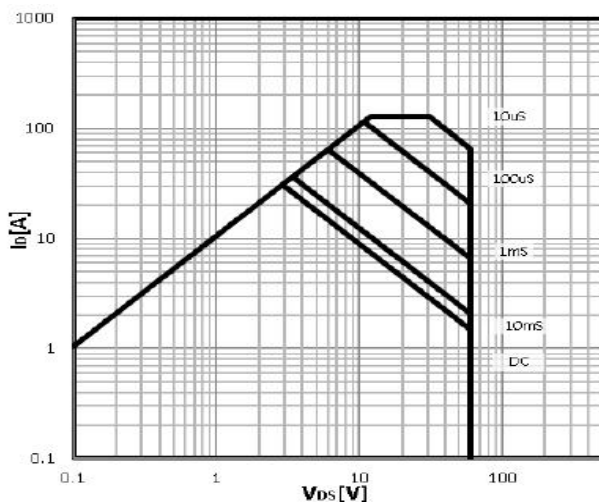


Fig12:Body Diode Forward Voltage Variation

$$-I_F = f(-V_{DS})$$

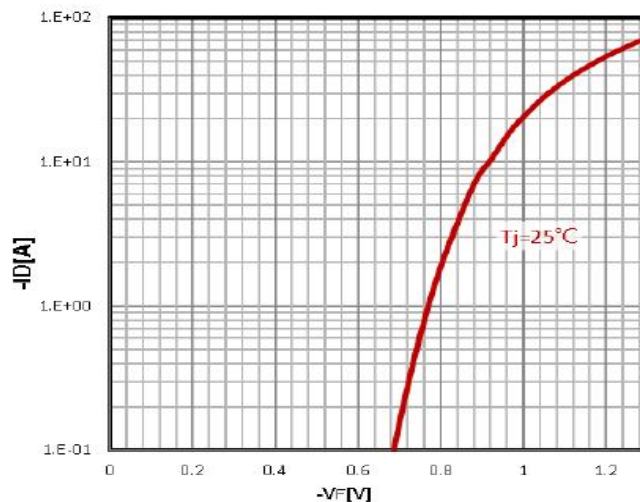
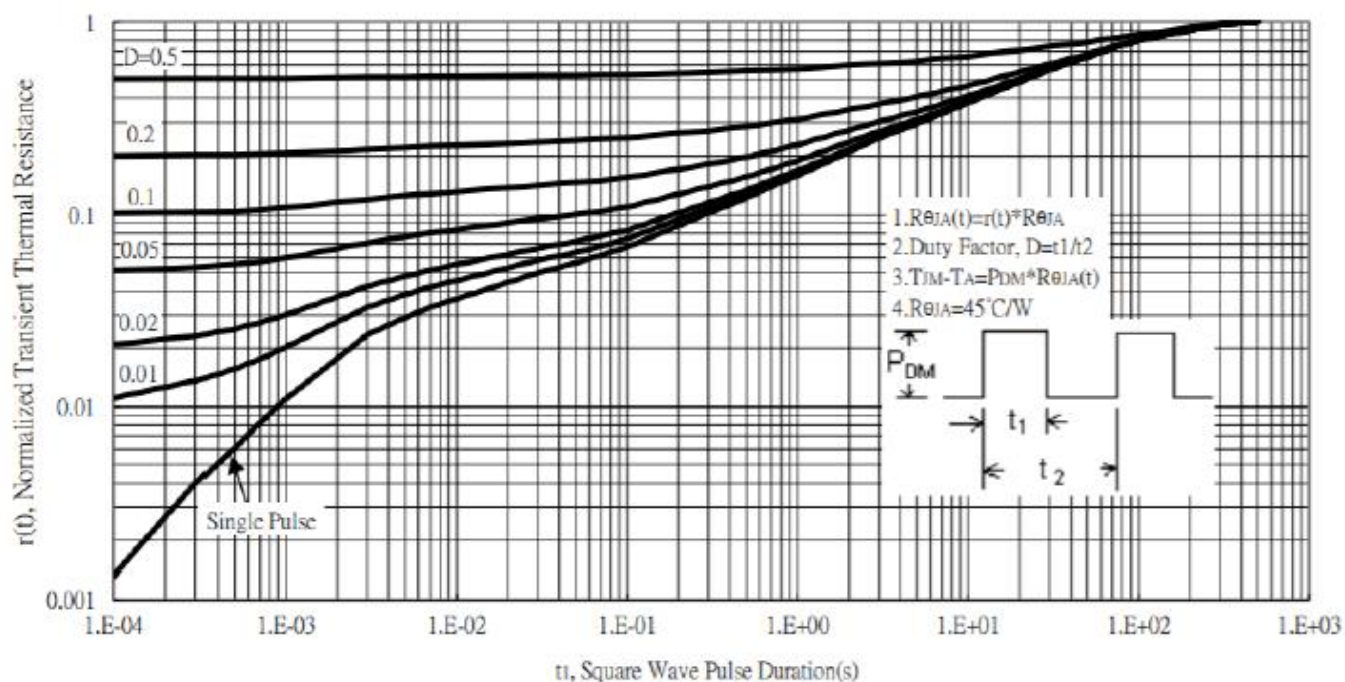
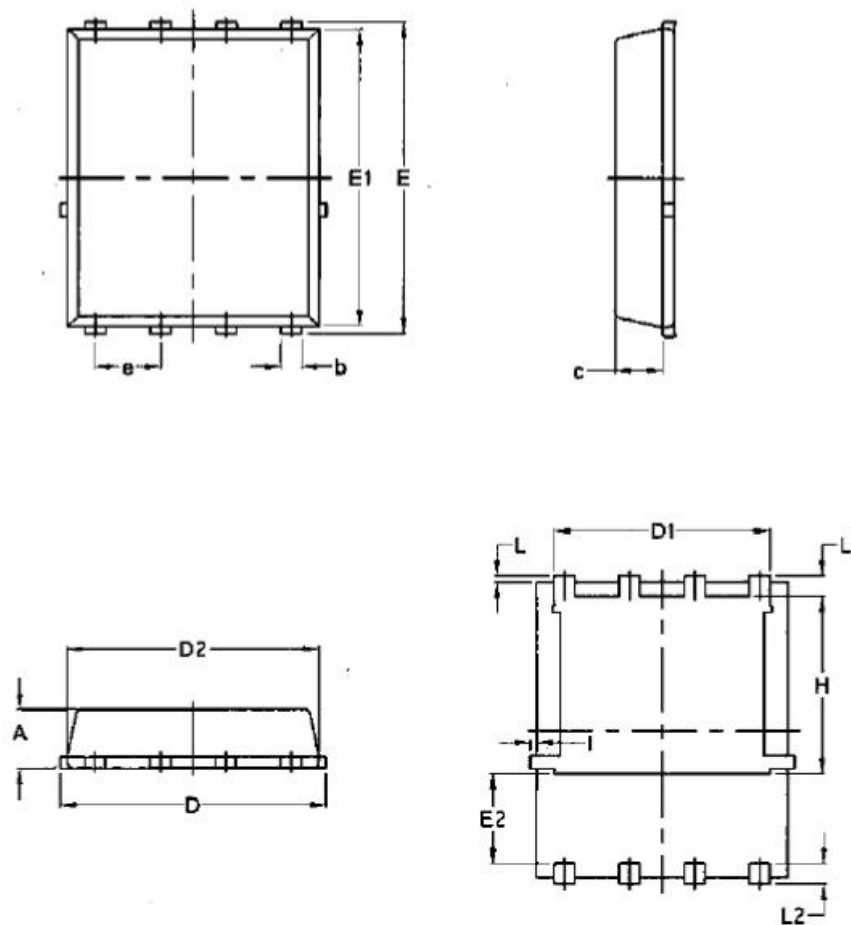


Fig12:Body Diode Forward Voltage Variation





Package Dimensions PDFN5*6-8L



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070



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